

PCN Number: CO-16311	Contact: Elizabeth La Greca		
Date Issued: February 15th, 2017	Title: Director, Sales Operations		
PCN Effective Date: March 1st, 2017	Phone: 1-858-795-0106		
Product(s) Affected: PE42540	Fax: 1-858-731-9499		
Sample Availability: February 15th, 2017	Email: pcn@psemi.com		
Change Control Board Approval #: CO-16311			
Change Category:			
Wafer Fabrication Process	Shipping/Labeling		
	Shipping/Labeling Equipment		
Wafer Fabrication Process			
Wafer Fabrication Process	Equipment		
Wafer Fabrication Process Design/Mask Change Singulation Process	Equipment Material		

Purpose of Change:

Transition to an improved laminate package material for the PE42540.

Description of Change:

Assembly supplier discontinuing current production process (electroless NiAu - ENIG) laminate plating finish and transitioning to (electroless NiPdAu - ENEPIG), an industry standard. Peregrine is taking the opportunity to make this transition in order to assure ongoing laminate supply with improved solderability, reliability and performance.

Reliability, form, fit or function is not affected by this change.

Beginning <u>March 1st, 2017</u>, all parts shipped to the customers will be manufactured in the ENEPIG plating finish.

Ordering code changes:

Original ordering codes (ENIG plating finish): PE42540LGBD-Z, EK42540-04 New ordering codes (ENEPIG plating finish): PE42540D-Z, EK42540-05



Qualification Summary:

Package Laminate Comparison			
Old Laminate	New Laminate		
ENIG	ENEPIG		
Nickel, Gold	Nickel, Palladium, Gold		
0.005 mm min.	0.003-0.007 mm		
NA	0.00005-0.0003 mm		
0.00003-0.00015 mm	0.00003 mm min.		
	Old Laminate ENIG Nickel, Gold 0.005 mm min. NA		

Product reliability qualification passed. See customer qualification report (Appendix A).

Customer Acknowledgement of Receipt:

Change Denied	Name:	
(Include explanation in comments section below)	Title:	
Change Approved	Company:	
	Date:	
	Signature:	
Customer Comments:		



Appendix A – Reliability Qualification Summary



PE42540

Reliability Summary Report

Part Number(s):	PE42540	Product Family:	Switch	
Package Type:	32L 5x5 FCLGA	MSL Rating:	3	
Technology Platform:	UltraCMOS [®] 5			
Reliability Summary:	Based on the results of reliability testing, the PE42540 has met the reliability requirements for production.			

Table 1: Product Design Reliability Results

Test #	Test Performed	TEST METHOD/ Conditions	Duration	Sample Size (#LOT x SS)	Result
1	High Temperature Operating Life (HTOL)	JESD22-A108; VDD= 3.6 V; VCTL= 3.6 V; T _A = T _J = 150 °C;	500 hrs.	1 x 77	Pass
2	ESD 2 Human Body Model (HBM)	JS-001 / MIL-STD-883 Model 3015.7 (All pins)	1kV	1 x 3	Pass
2		JS-001 / MIL-STD-883 Model 3015.7 (RF Pins Only)	2kV	1 x 3	Pass
3	ESD Machine Model (MM)	JEDEC JESD22-A115	100V	1 x 3	Pass
4	ESD Charged Device Model (CDM)	JEDEC JESD22-C101	1kV	1 x 3	Pass





PE42540

Reliability Summary Report

Table 2: Package Reliability Results

Test	Test Performed	TEST METHOD/ Conditions	Duration	Sample Size (#LOT x SS)	Result
5	High Temperature Operating Life (HTOL)	JESD22-A108; VDD= 3.6V; VCTL= 3.6V; T _J = 150°C	500 hrs.	3 x 77	Pass
6	High Temperature Storage Life (HTSL)	JESD22-A103; T _A = 150°C	1,000 hrs.	1 x 77	Pass
7	Moisture Sensitivity Level (MSL3)	JESD22-A113/J-STD- 020 Moisture Soak at 30°C/ 60% RH. Reflow at 260°C.	192 hrs. 3x Reflow	3 x 15	Pass
8	Highly Accelerated Stress Test (HAST)	JESD22-A110; T _A = 110°C; RH= 85%; VDD= 3.55 V	264 hrs.	3 x 45	Pass
9	Temperature Cycling (TC)	JESD22-A104; T _A = -55°C to +125°C	1,000 cyc.	3 x 45	Pass
10	Physical Dimensions	JESD22-B100 / Subcon specs.	-	3 x 3	Pass
11	Die Peel	Mil-Std-883 M2019.8 / Subcon specs.	-	3 x 2	Pass
12	Solderability	JESD22-B102 / Subcon specs.	-	3 x 3	Pass

Bump Process Qualification Report: DOC-82625 Technology Process Qualification Report: DOC-82626

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